



SCOPE OF ACCREDITATION

NonDestructive Testing

Element Rancho Dominguez
18100 S Wilmington Ave
Rancho Dominguez, CA 90220

This certificate expiration is updated based on periodic audits. The current expiration date and scope of accreditation are listed at: www.eAuditNet.com - Online QML (Qualified Manufacturer Listing).

In recognition of the successful completion of the PRI evaluation process, accreditation is granted to this facility to perform the following:

AC7114 Rev L - Nadcap Audit Criteria for NonDestructive Testing (NDT) Suppliers Accreditation (to be used on audits before 2 December 2018)

AC7114S Rev M - Nadcap Supplemental Audit Criteria for NonDestructive Testing (NDT) Suppliers Accreditation Program (to be used on audits before 2 December 2018)

- S-U1 Honeywell
- S-U10 GE
- S-U11 The Boeing Company
- S-U14 SAFRAN
- S-U16 Bell Helicopter
- S-U17 Sikorsky
- S-U18 Hamilton Sundstrand
- S-U2 Pratt & Whitney
- S-U20 GKN Aerospace Sweden
- S-U21 Eaton
- S-U3 Rolls-Royce PLC
- S-U4 Lockheed Martin
- S-U6 Rolls-Royce Corporation (refer to U3 Supplemental questions)
- S-U9 Textron Aviation

AC7114/1 Rev K - Nadcap Audit Criteria for NonDestructive Testing Facility Penetrant Survey (to be used on audits before 2 December 2018)

AC7114/1S Rev L - Nadcap Supplemental Audit Criteria for Penetrant Suppliers Accreditation

Program (to be used on audits before 2 December, 2018)

S-U1 Honeywell
S-U10 GE
S-U11 The Boeing Company
S-U14 SAFRAN
S-U16 Bell Helicopter
S-U17 Sikorsky
S-U18 Hamilton Sundstrand
S-U2 Pratt & Whitney
S-U20 GKN Aerospace Sweden
S-U21 Eaton
S-U3 Rolls-Royce PLC
S-U4 Lockheed Martin
S-U6 Rolls-Royce Corporation (refer to U3 Supplemental questions)
S-U9 Textron Aviation

AC7114/2 Rev K - Nadcap Audit Criteria for NonDestructive Testing Magnetic Particle Survey (to be used on audits before 2 December 2018)

AC7114/2S Rev L - Nadcap Supplemental Audit Criteria for NonDestructive Testing Magnetic Particle Survey (to be used before 2 December 2018)

S-U1 Honeywell
S-U10 GE
S-U11 The Boeing Company
S-U14 SAFRAN
S-U17 Sikorsky
S-U18 Hamilton Sundstrand
S-U21 Eaton
S-U4 Lockheed Martin
S-U9 Textron Aviation

AC7114/3 Rev K - Nadcap Audit Criteria for NonDestructive Testing Facility Ultrasonic Survey (to be used on audits before 2 December, 2018)

AC7114/3S Rev L - Nadcap Supplemental Audit Criteria for NonDestructive Testing Facility Ultrasonic Survey (to be used on audits before 2 December, 2018)

S-U11 The Boeing Company
S-U14 SAFRAN
S-U17 Sikorsky
S-U18 Hamilton Sundstrand
S-U2 Pratt & Whitney

S-U21 Eaton
S-U3 Rolls-Royce PLC
S-U4 Lockheed Martin
S-U6 Rolls-Royce Corporation (refer to U3 Supplemental questions)
S-U9 Textron Aviation

AC7114/4 Rev K - Nadcap Audit Criteria for NonDestructive Testing Facility Film Radiography Survey (to be used on audits before 2 December, 2018)

AC7114/4S Rev L - Nadcap Supplemental Audit Criteria for NonDestructive Testing Facility Film Radiography Survey (to be used on audits before 2 December 2018)

S-U1 Honeywell
S-U10 GE
S-U11 The Boeing Company
S-U14 SAFRAN
S-U16 Bell Helicopter
S-U17 Sikorsky
S-U18 Hamilton Sundstrand
S-U2 Pratt & Whitney
S-U21 Eaton
S-U3 Rolls-Royce PLC
S-U4 Lockheed Martin
S-U6 Rolls-Royce Corporation (refer to U3 Supplemental questions)
S-U9 Textron Aviation

AC7114/7 Rev B - Nadcap Audit Criteria for NonDestructive Testing Facility Ultrasonic Survey – Rotating Components (to be used on audits on/after 22 January 2017)

AC7114/7S Rev B - Nadcap Supplemental Audit Criteria for NonDestructive Testing Facility Ultrasonic Survey – Rotating Components (to be used on audits on/after 31 December 2017)

S-U1 Honeywell
S-U10 GE
S-U11 The Boeing Company
S-U14 SAFRAN
S-U17 Sikorsky
S-U18 Hamilton Sundstrand
S-U2 Pratt & Whitney
S-U20 GKN Aerospace Sweden
S-U21 Eaton
S-U3 Rolls-Royce PLC
S-U4 Lockheed Martin

S-U6 Rolls-Royce Corporation (refer to U3 Supplemental questions)
S-U9 Textron Aviation

**AC7114/10 - Nadcap Audit Criteria for NonDestructive Testing Facility Digital Radiography,
Utilizing Digital Detector Array (DDA) & Computed Radiography (CR) Utilizing Photostimulable
Luminescence (PSL) Survey**

CR